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500.43701X00

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: OKUDA, et al.

Serial No.: 10/809,464

Filed: 3/26/2004

Title: METHOD AND ITS APPARATUS FOR CLASSIFYING  
DEFECTS

Art Unit: 2621

**INFORMATION DISCLOSURE STATEMENT**  
**UNDER 37 CFR 1.97 & 1.98**

Mail Stop: DD  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

March 22, 2006

Sir:

In the matter of the above-identified application, applicant(s) are submitting herewith a copy of a communication in connection with a corresponding foreign application and copies of the non-US documents listed in the attached form equivalent to Form(s) PTO/SB/08A and/or PTO/SB/08B for the Examiner's consideration.

This information disclosure statement is being submitted before the mailing date of the first office action and with the following certification specified in 37 CFR 1.97(e).

On information and belief, I hereby certify that each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.

Each of the documents listed on the attached form equivalent to Form(s) PTO/SB/08A and/or PTO/SB/08B is in the English language.


It is respectfully requested that this information disclosure statement be considered by the Examiner.

Please charge any shortage in the fees due in connection with the filing of this

paper, including excess claim fees, to Deposit Account No. 01-2135 (500.43701X00), and please credit any excess fees to such deposit account.

Respectfully submitted,

ANTONELLI, TERRY, STOUT & KRAUS, LLP



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Melvin Kraus  
Registration No. 22,466

MK/jla  
1300 North Seventeenth Street  
Suite 1800  
Arlington, VA 22209  
Telephone: (703) 312-6600  
Fax: (703) 312-6666

Form PTO-1449 Equivalent	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DKT. NO. 500.43701X00	SERIAL NO. 10/809,464
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (Use several sheets if necessary)		<b>APPLICANT</b> OKUDA et al	
		<b>FILING DATE</b> March 26, 2004	<b>GROUP</b> 2621

**U.S. PATENT DOCUMENTS**

Ex. Initial	Doc. No.	Date	Name	Class	Subclass	Filing Date
AA						
AB						
AC						
AD						
AE						
AF						
AG						
AH						

**U.S. PATENT APPLICATIONS**

	Publication Number	Name	Publication Date
AI			
AJ			
AK			
AL			

**FOREIGN PATENT DOCUMENTS**

	Doc. No.	Date	Country	Class	Subclass	Translation/Abstract?	
						Yes	No
AM							
AN							
AO							
AP							
AQ							

**OTHER DOCUMENTS**

AR	Kuk Wo Ko, Such Cho, "Solder Joints Inspection Using A Neural Network and Fuzzy Rule-Based Classification Method", IEEE Transactions On Electronics Packaging Manufacturing, vol. 23, no. 2, April 2000 pp 93-103
AS	Xu, L, "Methods of Combining Multiple Classifiers And Their Applications To Handwriting Recognition" IEEE Transactions on Systems, Man and Cybernetics, vol. 22 no. 3 May 1992, pp 418-435
AT	Henry, et al "Application of ADC Techniques to Characterize Yield-Limiting Defects Identified With the Overlay of E-Test/Inspecting Data On Short Loop Process Testers" Advanced Semiconductor Manufacturing Conference, 1999 IEEE/SEMI Boston, MA 8-10 Sept. 1999 pp 330-337
<b>Examiner</b>	
<b>Date Considered</b>	